

## HEARING AID COMPATIBILITY

**Applicant Name:**  
 Samsung Electronics Co., Ltd.  
 129, Samsung-ro, Maetan dong,  
 Yeongtong-gu, Suwon-si  
 Gyeonggi-do 16677, Korea

**Date of Testing:**  
 9/3/2018 - 9/5/2018  
**Test Site/Location:**  
 PCTEST Lab, Columbia, MD, USA  
**Test Report Serial No.:**  
 1M1808290175-02.A3L

**FCC ID:** A3LSMG965U

**APPLICANT:** SAMSUNG ELECTRONICS CO., LTD.

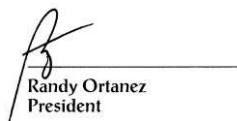
**Scope of Test:** Audio Band Magnetic Testing (T-Coil)  
**Application Type:** Class II Permissive Change  
**FCC Rule Part(s):** CFR §20.19(b)  
**HAC Standard:** ANSI C63.19-2011  
 CTIA Test Plan for Hearing Aid Compatibility Rev 3.1.1, May 2017  
 285076 D01 HAC Guidance v05  
 285076 D02 T-Coil testing for CMRS IP v03

**DUT Type:** Portable Handset  
**Model:** SM-G965U  
**Additional Model(s):** SM-G965U1, SM-G965W  
**Test Device Serial No.:** Pre-Production Sample [S/N: 37038]  
**Class II Permissive Change(s):** See FCC Change Document

**C63.19-2011 HAC Category:** T4 (SIGNAL TO NOISE CATEGORY, LTE B41 ONLY)

This report and category pertain only to LTE TDD Band 41; for full data, please refer to the previous Certification Test Report (T-Coil Test Report S/N: 1M1711060289-14-R4.A3L). The overall category rating of the device is determined by the lowest rating obtained over all air interfaces supported by the device. This wireless portable device has been shown to be hearing-aid compatible for LTE TDD Band 41, under the above rated category, specified in ANSI/IEEE Std. C63.19-2011 and has been tested in accordance with the specified measurement procedures. Hearing-Aid Compatibility is based on the assumption that all production units will be designed electrically identical to the device tested in this report. Test results reported herein relate only to the item(s) tested. North America bands only.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.





Randy Ortanez  
 President



Lab Code: 20020221-00





<b>FCC ID:</b> A3LSMG965U		<b>HAC (T-COIL) TEST REPORT</b>		<b>Approved by:</b> Quality Manager
<b>Filename:</b> 1M1808290175-02.A3L	<b>Test Dates:</b> 9/3/2018 - 9/5/2018	<b>DUT Type:</b> Portable Handset	Page 1 of 45	

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# 1. INTRODUCTION

On July 10, 2003, the Federal Communications Commission (FCC) adopted new rules requiring wireless manufacturers and service providers to provide digital wireless phones that are compatible with hearing aids. The FCC has modified the exemption for wireless phones under the Hearing Aid Compatibility Act of 1998 (HAC Act) in WT Docket 01-309 RM-8658<sup>1</sup> to extend the benefits of wireless telecommunications to individuals with hearing disabilities. These benefits encompass business, social and emergency communications, which increase the value of the wireless network for everyone. An estimated more than 10% of the population in the United States show signs of hearing impairment and of that fraction, almost 80% use hearing aids. Approximately 500 million people worldwide and 30 million people in the United States suffer from hearing loss.

## Compatibility Tests Involved:

The standard calls for wireless communications devices to be measured for:

- RF Electric-field emissions
- T-coil mode, magnetic-signal strength in the audio band
- T-coil mode, magnetic-signal frequency response through the audio band
- T-coil mode, magnetic-signal and noise articulation index

The hearing aid must be measured for:

- RF immunity in microphone mode
- RF immunity in T-coil mode

In the following tests and results, this report includes the evaluation for a wireless communications device.

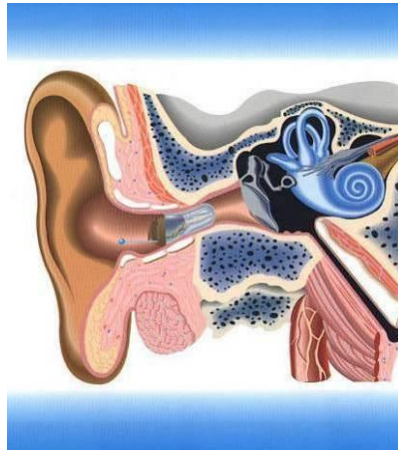




Figure 1-1 Hearing Aid *in-vitu*

<sup>1</sup> FCC Rule & Order, WT Docket 01-309 RM-8658

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## 2. DUT DESCRIPTION



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Applicant: Samsung Electronics Co., Ltd.  
129, Samsung-ro, Maetan dong,  
Yeongtong-gu, Suwon-si  
Gyeonggi-do 16677, Korea  
Model(s): SM-G965U  
Additional Model(s): SM-G965U1, SM-G965W  
Serial Number: 37038  
HW Version: REV1.1  
SW Version: G965U.001  
Antenna: Internal Antenna  
DUT Type: Portable Handset

### I. LTE Band Selection

This device supports the following pair of LTE bands with similar frequencies: LTE B38 & B41. This pair of LTE bands has the same target power and shares the same transmission path. Since the supported frequency span for the smaller LTE band is completely covered by the larger LTE band, only the larger LTE band (LTE B41) was evaluated for hearing-aid compliance.

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**Table 2-1**  
**Table 2-1: SM-G965U & SM-G965U1 HAC Air Interfaces**

Air-Interface	Band (MHz)	Type Transport	HAC Tested	Simultaneous But Not Tested	Name of Voice Service	Audio Codec Evaluated
CDMA	835	VO	No <sup>3</sup>	Yes: WIFI or BT	CMRS Voice <sup>1</sup>	EVRC
	1900					
GSM	EvDO	VD	No <sup>3</sup>	Yes: WIFI or BT	Google Duo <sup>2</sup>	OPUS
	850	VO	No <sup>3</sup>	Yes: WIFI or BT	CMRS Voice <sup>1</sup>	EFR
	1900					
UMTS	GPRS/EDGE	VD	No <sup>3</sup>	Yes: WIFI or BT	Google Duo <sup>2</sup>	OPUS
	850	VD	No <sup>3</sup>	Yes: WIFI or BT	CMRS Voice <sup>1</sup>	NB AMR
	1700					
	1900					
LTE (FDD)	HSPA	VD	No <sup>3</sup>	Yes: WIFI or BT	Google Duo <sup>2</sup>	OPUS
	680 (B71)	VD	No <sup>3</sup>	Yes: WIFI or BT	VoLTE <sup>1</sup> , Google Duo <sup>2</sup>	VoLTE: NB AMR, WB AMR, EVS Google Duo: OPUS
	700 (B12)					
	700 (B17)					
	780 (B13)					
	790 (B14)					
	850 (B5)					
	850 (B26)					
	1700 (B4)					
	1700 (B66)					
	1900 (B2)					
	1900 (B25)					
	2300 (B30)					
2500 (B7)						
LTE (TDD)	2600 (B38)	VD	Yes	Yes: WIFI or BT	VoLTE <sup>1</sup> , Google Duo <sup>2</sup>	VoLTE: NB AMR, WB AMR, EVS Google Duo: OPUS
	2600 (B41)					
WIFI	2450	VD	No <sup>3</sup>	Yes: CDMA, GSM, UMTS, or LTE	VoWIFI <sup>2</sup> , Google Duo <sup>2</sup>	VoWIFI: NB AMR, WB AMR, EVS Google Duo: OPUS
	5200 (U-NII 1)					
	5300 (U-NII 2A)					
	5500 (U-NII 2C)					
	5800 (U-NII 3)					
BT	2450	DT	No	Yes: CDMA, GSM, UMTS, or LTE	N/A	N/A
Type Transport VO = Voice Only DT = Digital Data - Not intended for CMRS Service VD = CMRS and IP Voice over Data Transport			Notes: <sup>1</sup> Reference level in accordance with 7.4.2.1 of ANSI C63.19-2011 and July 2012 C63 VoLTE Interpretation. <sup>2</sup> Reference level is -20dBm0 in accordance with FCC KDB 285076 D02 <sup>3</sup> This report only pertains to LTE Band 41 for VoLTE. For full data, please refer to the previous Certification Test Report (T-Coil Test Report S/N: 1M1711060289-14-R4.A3L).			

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**Table 2-2**  
**Table 2-2: SM-G965W HAC Air Interfaces**

Air-Interface	Band (MHz)	Type Transport	HAC Tested	Simultaneous But Not Tested	Name of Voice Service	Audio Codec Evaluated
GSM	850	VO	No <sup>3</sup>	Yes: WIFI or BT	CMRS Voice <sup>1</sup>	EFR
	1900					
UMTS	GPRS/EDGE	DT	No <sup>3</sup>	Yes: WIFI or BT	Google Duo <sup>2</sup>	OPUS
	850	VD	No <sup>3</sup>	Yes: WIFI or BT	CMRS Voice <sup>1</sup>	NB AMR
	1700					
	1900					
HSPA	DT	No <sup>3</sup>	Yes: WIFI or BT	Google Duo <sup>2</sup>	OPUS	
LTE (FDD)	700 (B12)	DT	No <sup>3</sup>	Yes: WIFI or BT	VoLTE <sup>1</sup> , Google Duo <sup>2</sup>	VoLTE: NB AMR, WB AMR, EVS Google Duo: OPUS
	700 (B17)					
	780 (B13)					
	850 (B5)					
	1700 (B4)					
	1700 (B66)					
	1900 (B2)					
	1900 (B25)					
2300 (B30)						
2500 (B7)						
LTE (TDD)	2600 (B38)	DT	Yes	Yes: WIFI or BT	VoLTE <sup>1</sup> , Google Duo <sup>2</sup>	VoLTE: NB AMR, WB AMR, EVS Google Duo: OPUS
	2600 (B41)					
WIFI	2450	DT	No <sup>3</sup>	Yes: GSM, UMTS, or LTE	VoWIFI <sup>2</sup> , Google Duo <sup>2</sup>	VoWIFI: NB AMR, WB AMR, EVS Google Duo: OPUS
	5200 (U-NII 1)					
	5300 (U-NII 2A)					
	5500 (U-NII 2C)					
5800 (U-NII 3)						
BT	2450	DT	No	Yes: GSM, UMTS, or LTE	N/A	N/A
Type Transport VO = Voice Only DT = Digital Data - Not intended for CMRS Service VD = CMRS and IP Voice over Data Transport			Notes: <sup>1</sup> Reference level in accordance with 7.4.2.1 of ANSI C63.19-2011 and July 2012 C63 VoLTE Interpretation. <sup>2</sup> Reference level is -20dBm0 in accordance with FCC KDB 285076 D02 <sup>3</sup> This report only pertains to LTE Band 41 for VoLTE. For full data, please refer to the previous Certification Test Report (T-Coil Test Report S/N: 1M1711060289-14-R4.A3L).			

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### 3. ANSI C63.19-2011 PERFORMANCE CATEGORIES

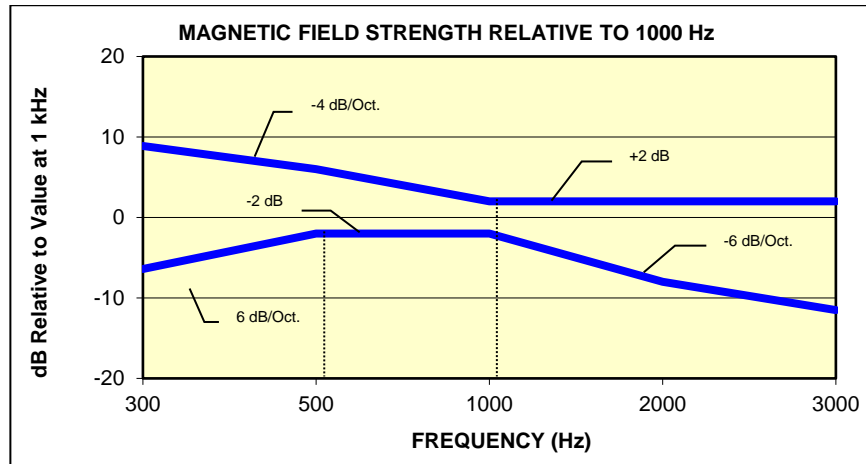
#### I. MAGNETIC COUPLING

##### Axial and Radial Field Intensity

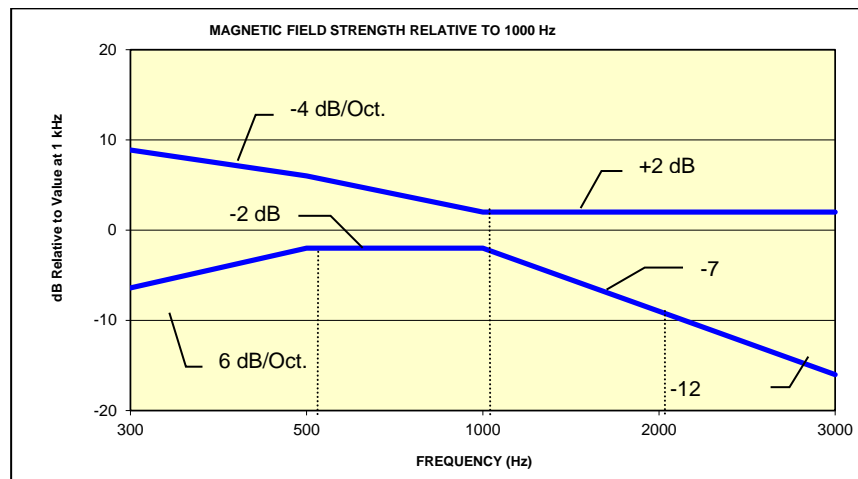
All orientations of the magnetic field, in the axial and radial position along the measurement plane shall be  $\geq -18$  dB(A/m) at 1 kHz in a 1/3 octave band filter per §8.3.1.

##### Frequency Response

The frequency response of the axial component of the magnetic field shall follow the response curve specified in EIA RS-504-1983, over the frequency range 300 Hz – 3000 Hz per §8.3.2.



**Figure 3-1**  
Magnetic field frequency response for Wireless Devices with an axial field  $\leq -15$  dB(A/m) at 1 kHz



**Figure 3-2**  
Magnetic Field frequency response for wireless devices with an axial field that exceeds  $-15$  dB(A/m) at 1 kHz

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## Signal Quality



The table below provides the signal quality requirement for the intended audio magnetic signal from a wireless device. Only the RF immunity of the hearing aid is measured in T-coil mode. It is assumed that a hearing aid can have no immunity to an interference signal in the audio band, which is the intended reception band for this mode. The only criterion that can be measured is the RF immunity in T-coil mode. This is measured using the same procedure as the audio coupling mode at the same levels.

The signal quality of the axial and radial components of the magnetic field was used to determine the T-coil mode category.

Category	Telephone RF Parameters
	Wireless Device Signal Quality [(Signal + Noise)-to-noise ratio in dB]
T1	0 to 10 dB
T2	10 to 20 dB
T3	20 to 30 dB
T4	> 30 dB

Table 3-1  
**Magnetic Coupling Parameters**

Note: The FCC limit for SNNR is 20dB and the test data margins will indicate a margin from the FCC limit for compliance.

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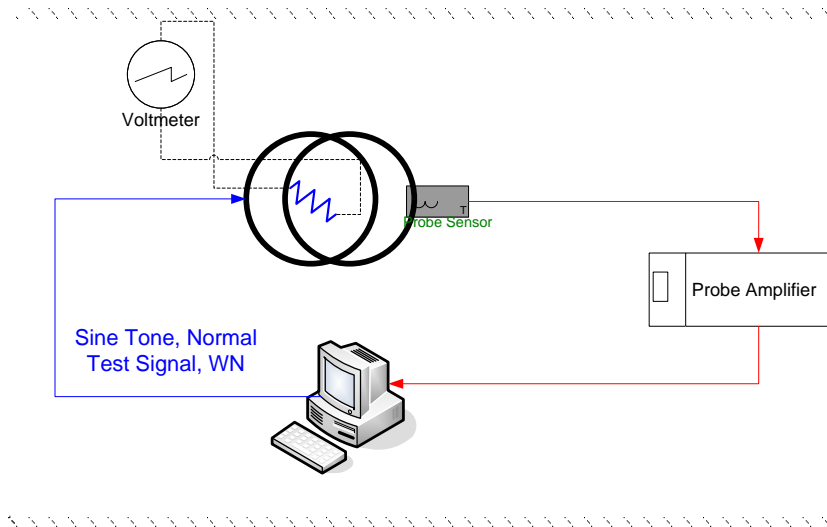
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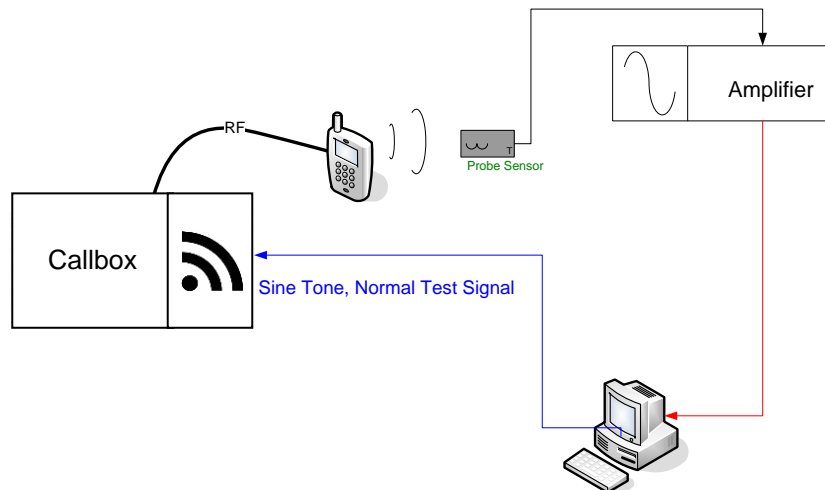
## 4. METHOD OF MEASUREMENT

### I. Test Setup



The equipment was connected as shown in an acoustic/RF hemi-anechoic chamber:



**Figure 4-1**  
**Validation Setup with Helmholtz Coil**



**Figure 4-2**  
**T-Coil Test Setup**

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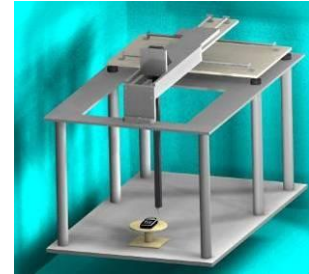
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## II. Scanning Mechanism

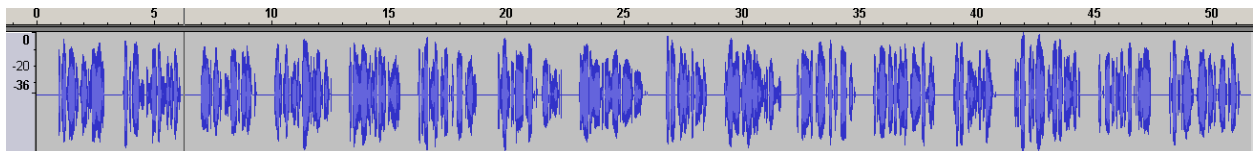
Manufacturer:	TEM
Accuracy:	± 0.83 cm/meter
Minimum Step Size:	0.1 mm
Maximum speed	6.1 cm/sec
Line Voltage:	115 VAC
Line Frequency:	60 Hz
Material Composite:	Delrin (Acetal)
Data Control:	Parallel Port
Dynamic Range (X-Y-Z):	45 x 31.75 x 47 cm
Dimensions:	36" x 25" x 38"
Operating Area:	36" x 49" x 55"
Reflections:	< -20 dB (in anechoic chamber)





**Figure 4-3**  
RF Near-Field Scanner

## III. 3GPP2 Normal Test Signal (Speech)

Manufacturer:	3GPP2 (TIA 1042 §3.3.1)
Stimulus Type:	Modified-IRS weighted, multi-talker speech signal, 4 Male and 4 Female speakers (alternating)
Single Sample Duration:	51.62 seconds
Activity Level:	77.4%



**Figure 4-4**  
Temporal Characteristic of Normal Test Signal

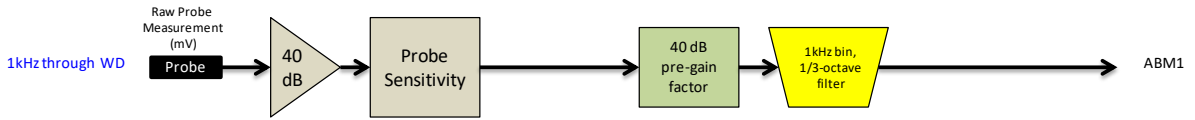
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ABM1 Measurement Block Diagram:



ABM2 Measurement Block Diagram:

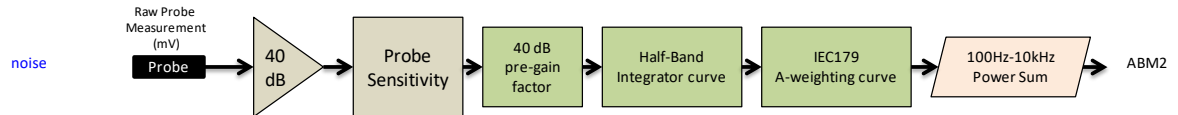


Figure 4-5 Magnetic Measurement Processing Steps

## IV. Test Procedure

1. Ambient Noise Check per C63.19 §7.3.1
  - a. Ambient interference was monitored using a Real-Time Analyzer between 100-10,000 Hz with 1/3 octave filtering.
  - b. “A-weighting” and Half-Band Integration was applied to the measurements.
  - c. Since this measurement was measured in the same method as ABM2 measurements, this level was verified to be more than 10 dB below the lowest measurement signal (which is the highest ABM2 measurement for a T4 WD). Therefore the maximum noise level for a T4 WD with an ABM1 = -18 dBA/m is:  

$$-18 - 30 - 10 = -58 \text{ dBA/m}$$
2. Measurement System Validation(See Figure 4-1)
  - a. The measurement system including the probe, pre-amplifier and acquisition system were validated as an entire system to ensure the reliability of test measurements.
  - b. ABM1 Validation  
 The magnetic field at the center of the Helmholtz coil is given by the equation (per C63.19 Annex D.10.1):

$$H_c = \frac{NI}{r\sqrt{1.25^3}} = \frac{N\left(\frac{V}{R}\right)}{r\sqrt{1.25^3}}$$

Where  $H_c$  = magnetic field strength in amperes per meter

$N$  = number of turns per coil

For the Helmholtz Coil,  $N=20$ ;  $r=0.08\text{m}$ ;  $R=10.2\Omega$  and using  $V=18\text{mV}$ :

$$H_c = \frac{20 \cdot \left(\frac{0.018}{10.2}\right)}{0.08 \cdot \sqrt{1.25^3}} = 0.316 \text{ A/m} \approx -10 \text{ dB(A/m)}$$

Therefore a pure tone of 1kHz was applied into the coils such that 18mV was observed across the resistor. The voltmeter used for measurement was verified to be capable of measurements in the audio band range. This theoretically generates an expected field of -10 dB(A/m) in the center of the Helmholtz coil which was used to validate the probe measurement at -10dB(A/m). This was verified to be within  $\pm 0.5$  dB of the -10dB(A/m) value (see Page 24).

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c. Frequency Response Validation

The frequency response through the Helmholtz Coil was verified to be within 0.5 dB relative to 1kHz, between 300 – 3000 Hz using the Normal signal as shown below:

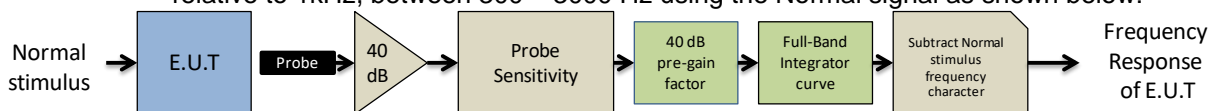


Figure 4-6 Frequency Response Validation

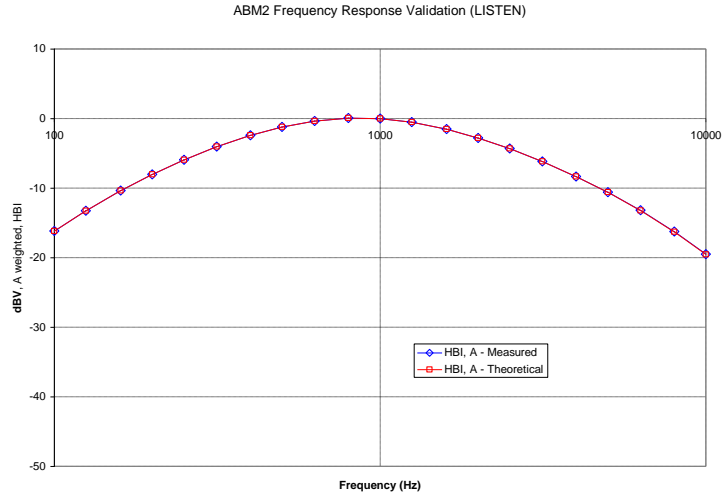
d. ABM2 Measurement Validation

WD noise measurements are filtered with A-weighting and Half-Band Integration over a frequency range of 100Hz – 10kHz to process ABM2 measurements. Below is the verification of the system processing A-weighting and Half-Band integration between system input to output within 0.5 dB of the theoretical result:

Table 4-1  
ABM2 Frequency Response Validation

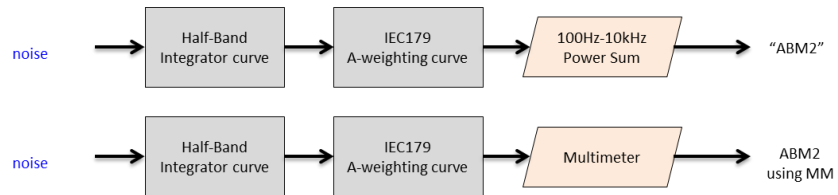
f (Hz)	HBI, A - Measured (dB re 1kHz)	HBI, A - Theoretical (dB re 1kHz)	dB Var.
100	-16.180	-16.170	-0.010
125	-13.257	-13.250	-0.007
160	-10.347	-10.340	-0.007
200	-8.017	-8.010	-0.007
250	-5.925	-5.920	-0.005
315	-4.045	-4.040	-0.005
400	-2.405	-2.400	-0.005
500	-1.212	-1.210	-0.002
630	-0.349	-0.350	0.001
800	0.071	0.070	0.001
1000	0.000	0.000	0.000
1250	-0.503	-0.500	-0.003
1600	-1.513	-1.510	-0.003
2000	-2.778	-2.780	0.002
2500	-4.316	-4.320	0.004
3150	-6.166	-6.170	0.004
4000	-8.322	-8.330	0.008
5000	-10.573	-10.590	0.017
6300	-13.178	-13.200	0.022
8000	-16.241	-16.270	0.029
10000	-19.495	-19.520	0.025

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**Figure 4-7**  
**ABM2 Frequency Response Validation**

The ABM2 result is a power sum from 100Hz to 10kHz with half-band integration and A-weighting. To verify the power sum measurement, a power sum over the full band was measured and verified to track with the source level (See Figure 4-8). Therefore the setup in this step was used to verify the power sum post-processing for ABM2 measurements. See below block diagram:



**Figure 4-8**  
**ABM2 Validation Block Diagram**

The power summed output results for a known input were compared to the multi-meter results to verify any deviation in the post-processing implemented with the power-sum.

**Table 4-2**  
**ABM2 Power Sum Validation**

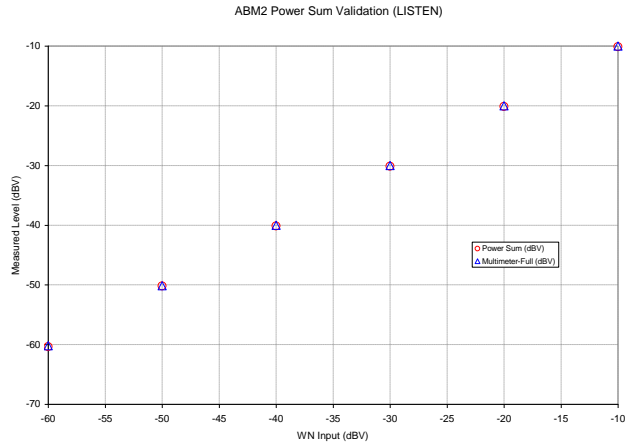
WN Input (dBV)	Power Sum (dBV)	Multimeter-Full (dBV)	Dev (dB)
-60	-60.36	-60.2	0.16
-50	-50.19	-50.13	0.06
-40	-40.14	-40.03	0.11
-30	-30.13	-30.01	0.12
-20	-20.12	-20	0.12
-10	-10.14	-10	0.14

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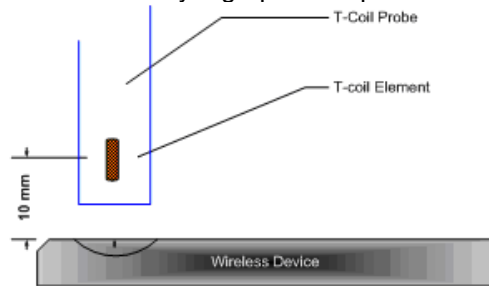


**Figure 4-9**  
**ABM2 Power Sum Validation**

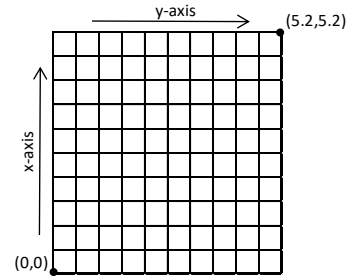
3. Measurement Test Setup

a. Fine scan above the WD (TEM)

- i. A multitone signal was applied to the handset such that the phone acoustic output was stable within 1dB over the probe settling time and with the acoustic output level at the C63.19 specified levels (below). The measurement step size was in 2 mm increments at a distance of 10 mm between the surface of the wireless device as shown below (note that in Figure 4-11, the grid is not to scale but merely a graphical representation of the coordinate system in use):



**Figure 4-10**  
**Measurement Distance**



**Figure 4-11**  
**Measurement Grid**

- ii. After scanning, the planar field maximum point was determined. The position of the probe was moved to this location to setup the test using the SoundCheck system.
- iii. These steps were repeated for all T-coil orientations (axial and radial) per Figure 4-13 after a T-coil orientation was fully measured with the SoundCheck system.



b. Speech Signal Setup to Base Station Simulator

- i. C63.19 Table 7-1 states audio reference input levels for various technologies:

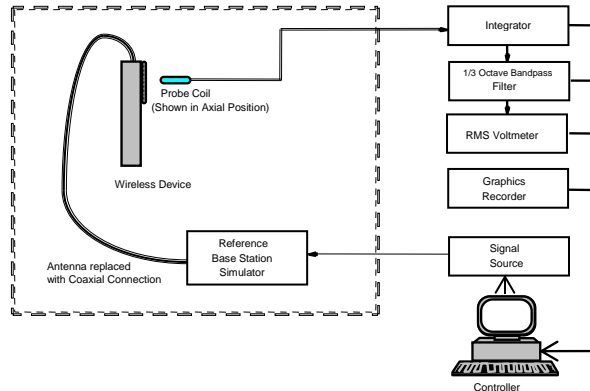
Standard	Technology	Input Level (dBm0)
TIA/EIA/IS-2000	CDMA	-18
J-STD-007	GSM (217)	-16
T1/T1P1/3GPP	UMTS (WCDMA)	-16

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- ii. See Section 5 for more information regarding CMW500 audio level settings for Voice Over LTE (VoLTE).
  - c. Real-Time Analyzer (RTA)
    - i. The Real-Time Analyzer was configured to analyze measurements using 1/3 Octave band weighted filtering.
  - d. WD Radio Configuration Selection
    - i. The device was chosen to be tested in the worst-case ABM2 condition (LTE configuration information can be found in Section 5).
- 4. Signal Quality Data Analysis
  - a. Narrow-band Magnetic Intensity
    - i. The standard specifies a 1kHz 1/3 octave band minimum field intensity for a sine tone. The ABM1 measurements were evaluated at 1kHz with 1/3 octave band filtering over an averaged period of 10 seconds.
  - b. Frequency Response
    - i. The appropriate frequency response curve was measured to curves in Figure 3-1 or Figure 3-2 between 300 – 3000 Hz using digital linear averaging (limit lines chosen according to measurement found in step 4a). A linear average over 3x the length of the artificial voice signal (3x sampling) was performed. A 10 second delay was configured in the measurement process of the stimulus to ensure handset vocoder latency effects and echo cancellation devices (if any) were appropriately stabilized during measurements.
    - ii. The appropriate post-processing was applied according to the system processing chain illustrated in Figure 4-6. All R10 frequencies were plotted with respect to 0dB at 1kHz value and aligned with respect to the EIA-504 mask.
    - iii. The margin is represented by the closest measured data point on the curve to the EIA-504 limit lines, in dB.
  - c. Signal Quality Index
    - i. Ensuring the WD was at maximum RF power, maximum volume, backlight off, display on, maximum contrast setting, keypad lights on (when possible) with no audio signal through the vocoder, the WD was measured over at least 100 Hz – 10,000 Hz, maximized over 5 seconds with a 50ms sample time for the ABM2 measurement (5 second time period is used in noise measurements under standards such as IEEE 269, etc.).
    - ii. After applying half-band integration and A-weighting to the result, a power sum was applied over each 1/3 octave bandwidth frequency for an ABM2 value.
    - iii. This result was subtracted from the ABM1 result in step 4.a, to obtain the Signal Quality.

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## V. Test Setup



**Figure 4-12**  
**Audio Magnetic Field Test Setup**

## VI. Deviation from C63.19 Test Procedure

Non-conducted RF connection due to inaccessible RF ports.



## VII. Air Interface Technologies Tested

All air interfaces which support voice capabilities over a managed CMRS or pre-installed OTT VoIP applications were tested for T-coil unless otherwise noted. See Table 2-1 and 2-2 for more details regarding which modes were tested.

## VIII. Wireless Device Channels and Frequencies

### 1. 4G (LTE) Modes

The middle channel for every applicable band and bandwidth combination was tested for each probe orientation. The band and bandwidth combination from each probe orientation resulting in the worst-case SNNR was additionally tested using low, and high channels for that band and bandwidth combination. Low-mid and mid-high channels are additionally tested for LTE TDD. See Tables 6-2 and 6-3 for LTE bandwidths and channels.

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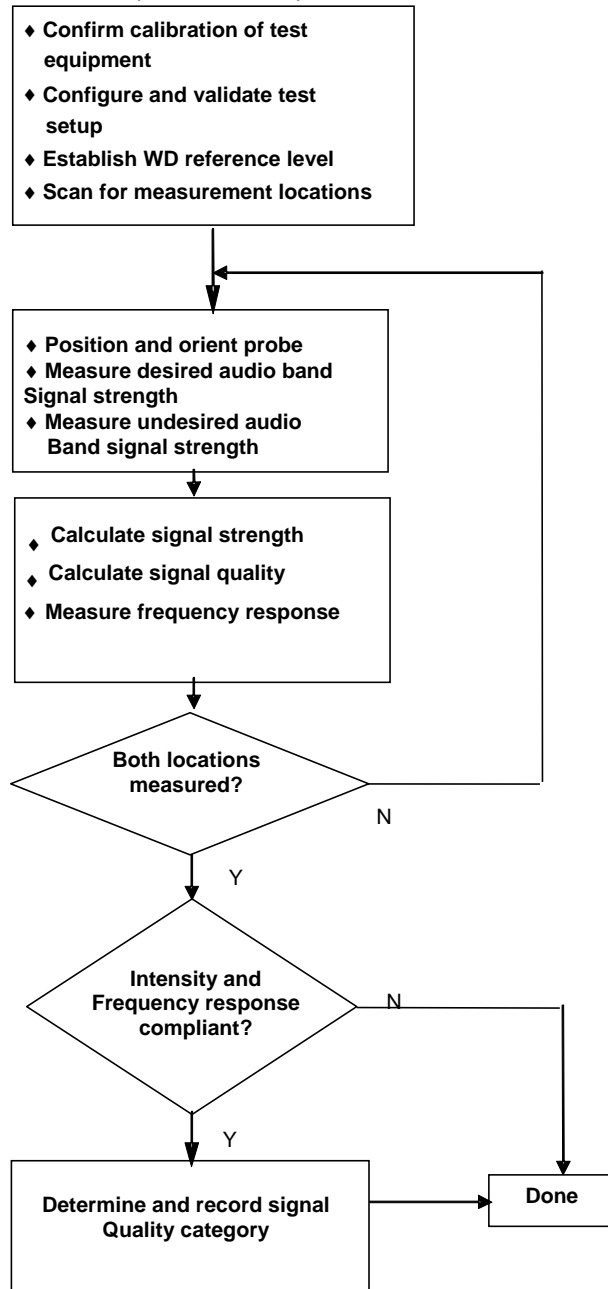
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## IX. Test Flow

The flow diagram below was followed (From C63.19):



**Figure 4-13**  
**C63.19 T-Coil Signal Test Process**

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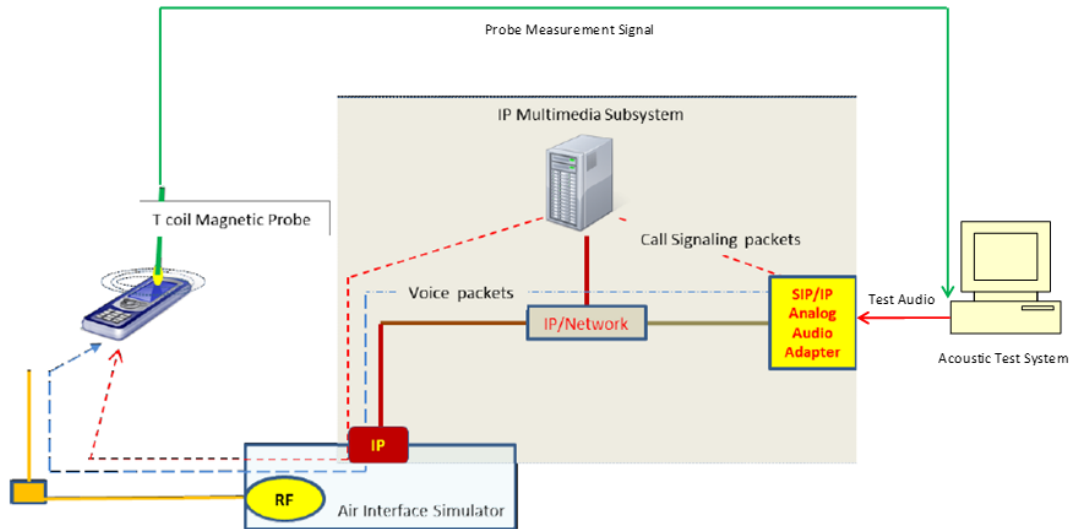
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## 5. VOLTE TEST SYSTEM SETUP AND DUT CONFIGURATION

### I. Test System Setup for VoLTE over IMS T-coil Testing

#### 1. Equipment Setup

The general test setup used for VoLTE over IMS is shown below. The callbox used when performing VoLTE over IMS T-coil measurements is a CMW500. The Data Application Unit (DAU) of the CMW500 was used to simulate the IP Multimedia Subsystem (IMS) server.



**Figure 5-1**  
Test Setup for VoLTE over IMS T-Coil Measurements

#### 2. Audio Level Settings

According to the July 2012 interpretations by the C63 Committee regarding the appropriate audio levels to be used for VoLTE over IMS T-coil testing, -16dBm0 shall be used for the normal speech input level. The CMW500 base station simulator was manually configured to ensure that the settings for speech input and full scale levels resulted in the -16dBm0 speech input level to the DUT for the VoLTE over IMS connection.

\* [http://c63.org/documents/misc/posting/new\\_interpretations.htm](http://c63.org/documents/misc/posting/new_interpretations.htm)

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## II. DUT Configuration for VoLTE over IMS T-coil Testing

### 1. Radio Configuration

An investigation was performed to determine the modulation and RB configuration to be used for testing. 16QAM, 1RB, 0RB offset was used for the testing as the worst-case configuration for the handset. See below table for SNNR comparison between different radio configurations:

**Table 5-1**  
**VoLTE over IMS SNNR by Radio Configuration**

Frequency [MHz]	Channel	Bandwidth [MHz]	Modulation	RB Size	RB Offset	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	SNNR [dB]
2593.0	40620	20	QPSK	1	0	2.32	-48.09	50.41
2593.0	40620	20	QPSK	1	50	2.26	-49.21	51.47
2593.0	40620	20	QPSK	1	99	2.37	-49.18	51.55
2593.0	40620	20	QPSK	50	0	2.07	-48.70	50.77
2593.0	40620	20	QPSK	50	25	2.18	-49.31	51.49
2593.0	40620	20	QPSK	50	50	2.07	-49.43	51.50
2593.0	40620	20	QPSK	100	0	2.05	-48.46	50.51
2593.0	40620	20	16QAM	1	0	2.29	-48.00	50.29
2593.0	40620	20	16QAM	1	50	2.15	-48.29	50.44
2593.0	40620	20	16QAM	1	99	2.38	-48.87	51.25
2593.0	40620	20	16QAM	50	0	2.19	-48.53	50.72
2593.0	40620	20	16QAM	50	25	2.22	-48.64	50.86
2593.0	40620	20	16QAM	50	50	2.29	-49.56	51.85
2593.0	40620	20	16QAM	100	0	2.43	-48.21	50.64
2593.0	40620	20	64QAM	1	0	2.01	-48.42	50.43
2593.0	40620	20	64QAM	1	50	2.28	-49.60	51.88
2593.0	40620	20	64QAM	1	99	2.31	-49.70	52.01
2593.0	40620	20	64QAM	50	0	2.40	-49.28	51.68
2593.0	40620	20	64QAM	50	25	2.37	-49.81	52.18
2593.0	40620	20	64QAM	50	50	2.21	-50.22	52.43
2593.0	40620	20	64QAM	100	0	2.17	-49.33	51.50

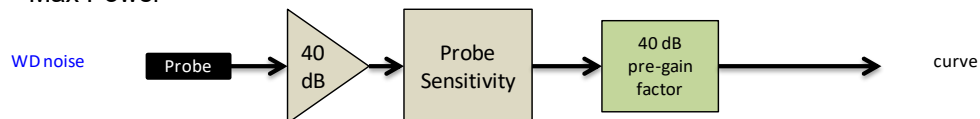
### 2. Codec Configuration

An investigation was performed to determine the audio codec configuration to be used for testing. The WB AMR 6.60kbps setting was used for the audio codec on the CMW500 for VoLTE over IMS T-coil testing. See below table for comparisons between different codecs and codec data rates:

**Table 5-2**  
**AMR Codec Investigation – VoLTE over IMS**

Codec Setting:	WB AMR 23.85kbps	WB AMR 6.60kbps	NB AMR 12.2kbps	NB AMR 4.75kbps	Orientation	Band / BW	Channel
ABM1 (dBA/m)	3.40	2.29	4.81	4.57	Axial	Band 41 (PC3) 20MHz	40620
ABM2 (dBA/m)	-47.66	-47.47	-47.41	-47.90			
Frequency Response	Pass	Pass	Pass	Pass			
S+N/N (dB)	51.06	49.76	52.22	52.47			

- Mute on; Backlight off; Max Volume; Max Contrast
- TPC = “Max Power”



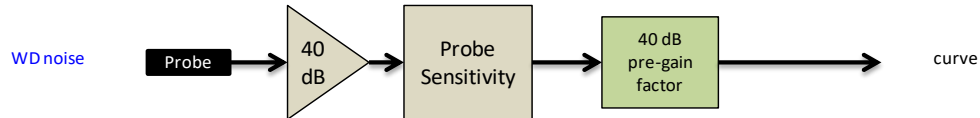
**Figure 5-2**  
**Audio Band Magnetic Curve Measurement Block Diagram**

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**Table 5-3**  
**EVS Codec Investigation - VoLTE over IMS**

Codec Setting:	EVS Primary SWB 13.2kbps	EVS Primary SWB 9.6kbps	EVS Primary WB 13.2kbps	EVS Primary WB 5.9kbps	EVS Primary NB 13.2kbps	EVS Primary NB 5.9kbps	Orientation	Band / BW	Channel
ABM1 (dBA/m)	7.22	7.02	7.29	5.21	6.84	6.00	Axial	Band 41 (PC3) 20MHz	40620
ABM2 (dBA/m)	-47.90	-47.82	-47.91	-47.98	-48.00	-47.96			
Frequency Response	Pass	Pass	Pass	Pass	Pass	Pass			
S+N/N (dB)	55.12	54.84	55.20	53.19	54.84	53.96			

- Mute on; Backlight off; Max Volume; Max Contrast
- TPC = "Max Power"



**Figure 5-3**  
**Audio Band Magnetic Curve Measurement Block Diagram**

### 3. LTE TDD Uplink-Downlink Configuration Investigation for VoLTE over IMS

An investigation was performed to determine the worst-case Uplink-Downlink configuration for VoLTE over IMS T-Coil testing.

Per 3GPP TS 36.211, the total frame length for each TDD radio frame of length  $T_f = 307200 \cdot T_s = 10$  ms, where  $T_s$  is a number of time units equal to  $1/(15000 \times 2048)$  seconds. Additionally, each radio frame consists of 10 subframes, each of length  $30720 \cdot T_s = 1$  ms, and subframes can be designated as uplink (U), downlink (D), or special subframe (S), depending on the Uplink-Downlink configuration as indicated in Table 4.2-2 of 3GPP TS 36.211. In the transmission duty factor calculation, the special subframe configuration with the shortest UpPTS duration within the special subframe is used and will be applied for measurement. From 3GPP TS 36.211 Table 4.2-1, the shortest UpPTS is  $2192 \cdot T_s$  which occurs in the normal cyclic prefix and special subframe configuration 4.

See table below outlining the calculated transmission duty cycles for each Uplink-Downlink configuration:

**Table 5-4**  
**Uplink-Downlink Configurations for Type 2 Frame Structures**

Uplink-downlink configuration	Downlink-to-Uplink Switch-point periodicity	Subframe number										Calculated Transmission Duty Cycle (%)
		0	1	2	3	4	5	6	7	8	9	
0	5 ms	D	S	U	U	U	D	S	U	U	U	61.4%
1	5 ms	D	S	U	U	D	D	S	U	U	D	41.4%
2	5 ms	D	S	U	D	D	D	S	U	D	D	21.4%
3	10 ms	D	S	U	U	U	D	D	D	D	D	30.7%
4	10 ms	D	S	U	U	D	D	D	D	D	D	20.7%
5	10 ms	D	S	U	D	D	D	D	D	D	D	10.7%
6	5 ms	D	S	U	U	U	D	S	U	U	D	51.4%

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**a. Power Class 3 Uplink-Downlink Configuration Investigation**

Power class 3 was evaluated with the following radio configuration: channel 40620, 20MHz BW, 16QAM, 1RB, 0RB Offset. For Power Class 3, all configurations (0-6) are supported. The configuration which resulted in the worst SNNR was used for full testing. Uplink-Downlink configuration 0 was used as the worst-case configuration for Power Class 3 VoLTE over IMS T-Coil testing. See table below for the SNNR comparison between each Uplink-Downlink configuration:

**Table 5-5  
Power Class 3 VoLTE over IMS SNNR by UL-DL Configuration**

Frequency [MHz]	Channel	Bandwidth [MHz]	Modulation	RB Size	RB Offset	UL-DL Configuration	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	SNNR [dB]
2593.0	40620	20	16QAM	1	0	0	2.36	-47.14	49.50
2593.0	40620	20	16QAM	1	0	1	2.18	-47.81	49.99
2593.0	40620	20	16QAM	1	0	2	2.32	-47.92	50.24
2593.0	40620	20	16QAM	1	0	3	2.01	-49.25	51.26
2593.0	40620	20	16QAM	1	0	4	2.07	-50.17	52.24
2593.0	40620	20	16QAM	1	0	5	2.09	-50.14	52.23
2593.0	40620	20	16QAM	1	0	6	2.16	-47.74	49.90

**b. Power Class 2 Uplink-Downlink Configuration Investigation**

Power Class 2 was evaluated with the following radio configuration: channel 40620, 20MHz BW, 16QAM, 1RB, 0RB Offset. For Power Class 2, configurations 1-5 are supported. The configuration which resulted in the worst SNNR was used for full testing. Uplink-Downlink configuration 1 was used as the worst-case configuration for Power Class 2 VoLTE over IMS T-Coil testing. See table below for the SNNR comparison between each Uplink-Downlink configuration:



**Table 5-6  
Power Class 2 VoLTE over IMS SNNR by UL-DL Configuration**

Frequency [MHz]	Channel	Bandwidth [MHz]	Modulation	RB Size	RB Offset	UL-DL Configuration	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	SNNR [dB]
2593.0	40620	20	16QAM	1	0	1	2.46	-42.02	44.48
2593.0	40620	20	16QAM	1	0	2	2.47	-42.81	45.28
2593.0	40620	20	16QAM	1	0	3	2.26	-42.55	44.81
2593.0	40620	20	16QAM	1	0	4	2.21	-42.77	44.98
2593.0	40620	20	16QAM	1	0	5	2.04	-43.28	45.32

Note: LTE TDD B41 Power Class 2 only supports UL-DL configurations 1-5, not 0 or 6.

**c. Conclusion**

Per the investigations above, UL-DL Configuration 0 was used to evaluate Power Class 3 VoLTE over IMS and UL-DL Configuration 1 was used to evaluate Power Class 2 VoLTE over IMS.

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## 6. TEST SUMMARY

**Table 6-1**  
**Consolidated Tabled Results**

		Freq. Response Margin		Magnetic Intensity Verdict		FCC SNNR Verdict		Margin from FCC Limit (dB)	C63.19-2011 Rating
		8.3.2		8.3.1		8.3.4			
C63.19 Section		Axial	Radial	Axial	Radial	Axial	Radial		
LTE TDD	B41	PASS	NA	PASS	PASS	PASS	PASS	-19.27	T4



### I. Raw Handset Data

**Table 6-2**  
**Raw Data Results for LTE B41 Power Class 3**

Mode	Orientation	Bandwidth	Channel	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	Ambient Noise [dB(A/m)]	Frequency Response Margin (dB)	S+N/N (dB)	FCC Limit (dB)	Margin from FCC Limit (dB)	C63.19-2011 Rating	Test Coordinates
LTE Band 41	Axial	20MHz	40620	2.78	-48.04	-61.92	1.72	50.82	20.00	-30.82	T4	2.4, 2.4
		15MHz	40620	2.45	-48.41		1.88	50.86	20.00	-30.86	T4	
		10MHz	40620	2.67	-48.74		1.84	51.41	20.00	-31.41	T4	
		5MHz	40620	2.74	-48.60		1.89	51.34	20.00	-31.34	T4	
	Radial	20MHz	40620	-4.34	-46.60	-62.02	N/A	42.26	20.00	-22.26	T4	2.4, 1.4
		15MHz	40620	-4.33	-46.95			42.62	20.00	-22.62	T4	
		10MHz	40620	-4.45	-47.93			43.48	20.00	-23.48	T4	
		5MHz	40620	-4.52	-48.27			43.75	20.00	-23.75	T4	

**Table 6-3**  
**Raw Data Results for LTE B41 Power Class 2**

Mode	Orientation	Bandwidth	Channel	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	Ambient Noise [dB(A/m)]	Frequency Response Margin (dB)	S+N/N (dB)	FCC Limit (dB)	Margin from FCC Limit (dB)	C63.19-2011 Rating	Test Coordinates
LTE Band 41	Axial	20MHz	40620	2.60	-43.02	-61.92	1.72	45.62	20.00	-25.62	T4	2.4, 2.4
		15MHz	40620	2.29	-42.76		1.67	45.05	20.00	-25.05	T4	
		10MHz	40620	2.30	-43.74		1.67	46.04	20.00	-26.04	T4	
		5MHz	41490	2.32	-43.52		1.87	45.84	20.00	-25.84	T4	
		5MHz	41055	2.19	-43.06		1.82	45.25	20.00	-25.25	T4	
		5MHz	40620	2.61	-42.38		1.75	44.99	20.00	-24.99	T4	
		5MHz	40185	2.31	-44.88		1.80	47.19	20.00	-27.19	T4	
		5MHz	39750	2.58	-46.01		1.72	48.59	20.00	-28.59	T4	
	Radial	20MHz	40620	-4.26	-46.48	-62.02	N/A	42.22	20.00	-22.22	T4	2.4, 1.4
		15MHz	40620	-3.85	-45.79			41.94	20.00	-21.94	T4	
		10MHz	40620	-4.10	-45.94			41.84	20.00	-21.84	T4	
		5MHz	41490	-4.36	-44.35			39.99	20.00	-19.99	T4	
		5MHz	41055	-4.62	-45.45			40.83	20.00	-20.83	T4	
		5MHz	40620	-4.38	-46.04			41.66	20.00	-21.66	T4	
		5MHz	40185	-4.24	-43.51			39.27	20.00	-19.27	T4	
		5MHz	39750	-4.33	-45.52			41.19	20.00	-21.19	T4	

FCC ID: A3LSMG965U	 PCTEST ENGINEERING LABORATORY, INC.	HAC (T-COIL) TEST REPORT		Approved by: Quality Manager
Filename: 1M1808290175-02.A3L	Test Dates: 9/3/2018 - 9/5/2018	DUT Type: Portable Handset	Page 22 of 45	

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## II. Test Notes

### A. General

1. Phone Condition: Mute on; Backlight off; Max Volume; Max Contrast
2. 'Radial' orientation refers to radial transverse.
3. Hearing Aid Mode (**Phone→Settings→More Settings→Hearing aids**) was set to ON for Frequency Response compliance
4. Speech Signal: 3GPP2 Normal Test Signal
5. Bluetooth and WIFI were disabled for 2G/3G/4G modes while testing.
6. The Margin from FCC limit column indicates a margin from the FCC limit for compliance (T4).

### B. LTE TDD

1. Power Configuration: TPC = "Max Power"
2. Radio Configuration: 16QAM, 1RB, 0RB offset
3. Power Class 3 Uplink-Downlink configuration: 0
4. Power Class 2 Uplink-Downlink configuration: 1
5. Vocoder Configuration: WB AMR 6.60kbps
6. Speech Signal: 3GPP2 Normal Test Signal
7. The worst-case band and bandwidth combination for each probe orientation is additionally tested on the low, low-mid, mid-high and high channels for those combinations. LTE Band 41 (PC2) at 5MHz is the worst-case for both Axial and Radial probe orientations.

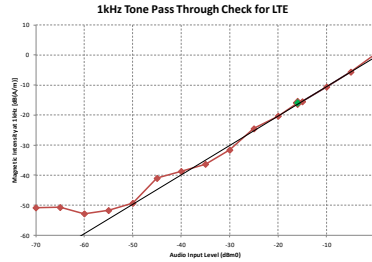
<b>FCC ID:</b> A3LSMG965U		<b>HAC (T-COIL) TEST REPORT</b>		<b>Approved by:</b> Quality Manager
<b>Filename:</b> 1M1808290175-02.A3L	<b>Test Dates:</b> 9/3/2018 - 9/5/2018	<b>DUT Type:</b> Portable Handset	Page 23 of 45	

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### III. 1 kHz Vocoder Application Check





This model was verified to be within the linear region for ABM1 measurements at -16 dBm0 for VoLTE over IMS. This measurement was taken in the axial configuration above the maximum location.

### IV. T-Coil Validation Test Results

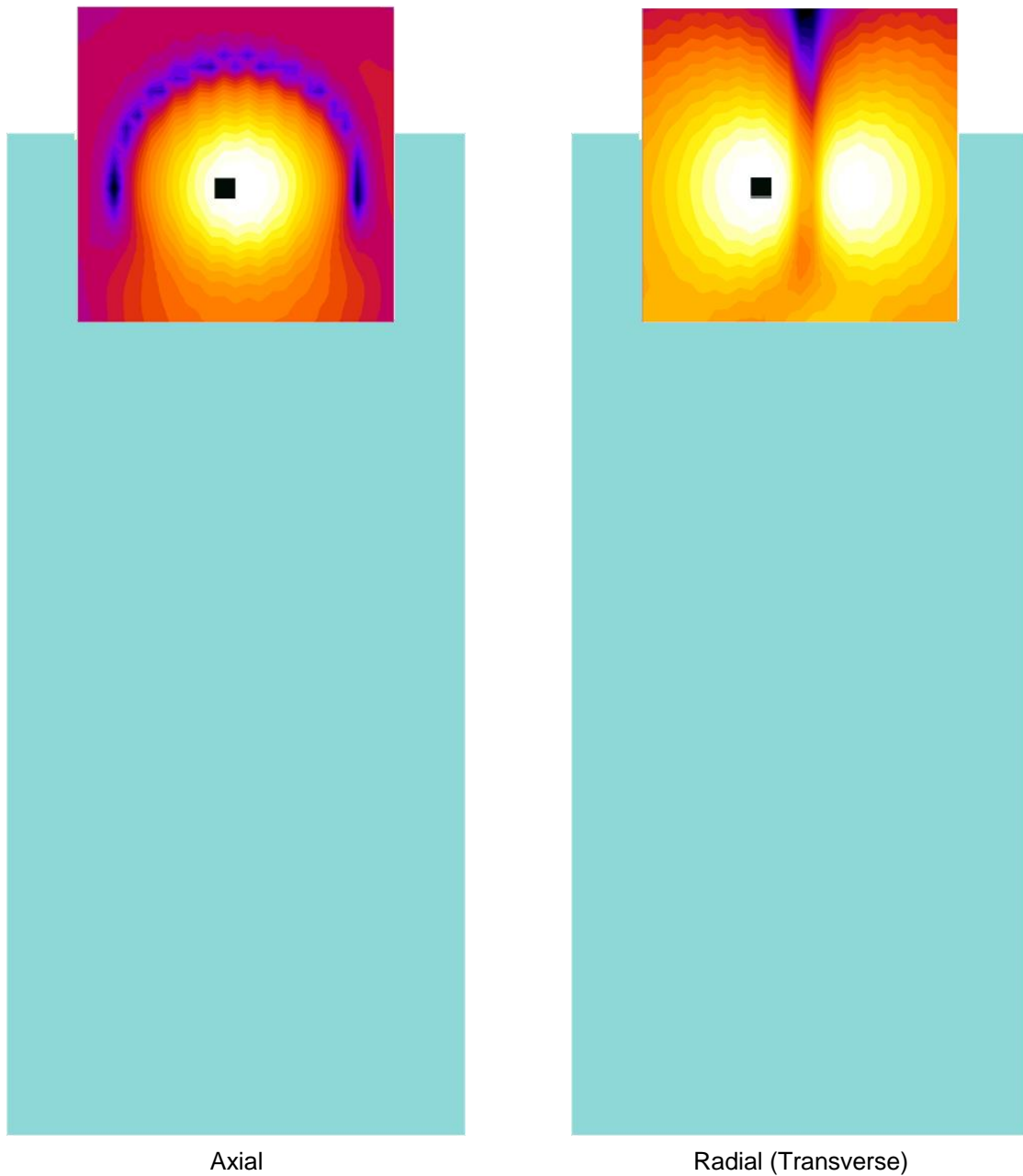
**Table 6-4**  
**Helmholtz Coil Validation Table of Results**

Item	Target	Result	Verdict
<b>Axial</b>			
Magnetic Intensity, -10 dBA/m	$-10 \pm 0.5 \text{ dB}$	-10.185	<b>PASS</b>
Environmental Noise	< -58 dBA/m	-61.92	<b>PASS</b>
Frequency Response, from limits	> 0 dB	0.70	<b>PASS</b>
<b>Radial</b>			
Magnetic Intensity, -10 dBA/m	$-10 \pm 0.5 \text{ dB}$	-10.277	<b>PASS</b>
Environmental Noise	< -58 dBA/m	-62.02	<b>PASS</b>
Frequency Response, from limits	> 0 dB	0.70	<b>PASS</b>

FCC ID: A3LSMG965U	 PCTEST ENGINEERING LABORATORY, INC.	HAC (T-COIL) TEST REPORT		Approved by: Quality Manager
Filename: 1M1808290175-02.A3L	Test Dates: 9/3/2018 - 9/5/2018	DUT Type: Portable Handset		Page 24 of 45





## V. ABM1 Magnetic Field Distribution Scan Overlays



**Figure 6-1**  
**T-Coil Scan Overlay Magnetic Field Distributions**

**Notes:**

1. Final measurement locations are indicated by a cursor on the contour plots.
2. See Test Setup Photographs for actual WD overlay.

FCC ID: A3LSMG965U		<b>HAC (T-COIL) TEST REPORT</b>		<b>Approved by:</b> Quality Manager
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## 7. MEASUREMENT UNCERTAINTY



**Table 7-1  
Uncertainty Estimation Table**

Contribution	Data +/- %	Data +/- dB	Data Type	Probability distribution	Divisor	Standard uncertainty	Standard Uncertainty (dB)
ABM Noise	7.0%	0.29	Std. Dev.	Normal k=1	1.00	7.0%	
RF Reflections	4.7%	0.20	Specification	Rectangular	1.73	2.7%	
Reference Signal Level	12.2%	0.50	Specification	Rectangular	1.73	7.0%	
Positioning Accuracy	10.0%	0.41	Uncertainty	Rectangular	1.73	5.8%	
Probe Coil Sensitivity	12.2%	0.50	Specification	Rectangular	1.73	7.0%	
Probe Linearity	2.4%	0.10	Std. Dev.	Normal k=1	1.00	2.4%	
Cable Loss	2.8%	0.12	Specification	Rectangular	1.73	1.6%	
Frequency Analyzer	5.0%	0.21	Specification	Rectangular	1.73	2.9%	
System Repeatability	5.0%	0.21	Std. Dev.	Normal k=1	1.00	5.0%	
WD Repeatability	9.0%	0.37	Std. Dev.	Normal k=1	1.00	9.0%	
Positioner Accuracy	1.0%	0.04	Specification	Rectangular	1.73	0.6%	
Combined standard uncertainty, uc (k=1)						17.7%	0.71
Expanded uncertainty (k=2), 95% confidence level						35.3%	1.31

Notes:

1. Test equipments are calibrated according to techniques outlined in NIS81, NIS3003 and NIST Tech Note 1297.
2. All equipments have traceability according to NIST. Measurement Uncertainties are defined in further detail in NIS 81 and NIST Tech Note 1297 and UKAS M3003.



Measurement uncertainty reflects the quality and accuracy of a measured result as compared to the true value. Such statements are generally required when stating results of measurements so that it is clear to the intended audience that the results may differ when reproduced by different facilities. Measurement results vary due to the measurement uncertainty of the instrumentation, measurement technique, and test engineer. Most uncertainties are calculated using the tolerances of the instrumentation used in the measurement, the measurement setup variability, and the technique used in performing the test. While not generally included, the variability of the equipment under test also figures into the overall measurement uncertainty. Another component of the overall uncertainty is based on the variability of repeated measurements (so-called Type A uncertainty). This may mean that the Hearing Aid compatibility tests may have to be repeated by taking down the test setup and resetting it up so that there are a statistically significant number of repeat measurements to identify the measurement uncertainty. By combining the repeat measurement results with that of the instrumentation chain using the technique contained in NIS 81 and NIS 3003, the overall measurement uncertainty was estimated.

FCC ID: A3LSMG965U		HAC (T-COIL) TEST REPORT		Approved by: Quality Manager
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## 8. EQUIPMENT LIST

**Table 8-1  
Equipment List**

Manufacturer	Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
Dell	Latitude E6540	SoundCheck Acoustic Analyzer Laptop	4/11/2017	Biennial	4/11/2019	7BFNM32
Listen	SoundConnect	Microphone Power Supply	12/2/2016	Biennial	12/2/2018	PS2612
RME	Fireface UC	Soundcheck Acoustic Analyzer External Audio Interface	4/11/2017	Biennial	4/11/2019	23528889
Rohde & Schwarz	CMW500	Wideband Radio Communication Tester	1/19/2018	Annual	1/19/2019	162125
Rohde & Schwarz	CMW500	Wideband Radio Communication Tester	8/3/2018	Annual	8/3/2019	140144
Seekonk	NC-100	Torque Wrench (8" lb)	5/10/2018	Biennial	5/10/2020	21053
TEM	C63.19	Helmholtz Coil	12/7/2016	Biennial	12/7/2018	925
TEM	Radial T-Coil Probe	Radial T-Coil Probe	12/7/2016	Biennial	12/7/2018	TEM-1130
TEM	Axial T-Coil Probe	Axial T-Coil Probe	12/7/2016	Biennial	12/7/2018	TEM-1124
TEM		HAC System Controller with Software	N/A		N/A	N/A
TEM		HAC Positioner	N/A		N/A	N/A

<b>FCC ID:</b> A3LSMG965U		<b>HAC (T-COIL) TEST REPORT</b>		<b>Approved by:</b> Quality Manager
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## 9. TEST DATA

See following attached pages for Test Data.

<b>FCC ID:</b> A3LSMG965U		<b>HAC (T-COIL) TEST REPORT</b>		<b>Approved by:</b> Quality Manager
<b>Filename:</b> 1M1808290175-02.A3L	<b>Test Dates:</b> 9/3/2018 - 9/5/2018	<b>DUT Type:</b> Portable Handset	Page 28 of 45	

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**PCTEST Hearing-Aid Compatibility Facility**

**DUT: HH Coil – SN: 925**

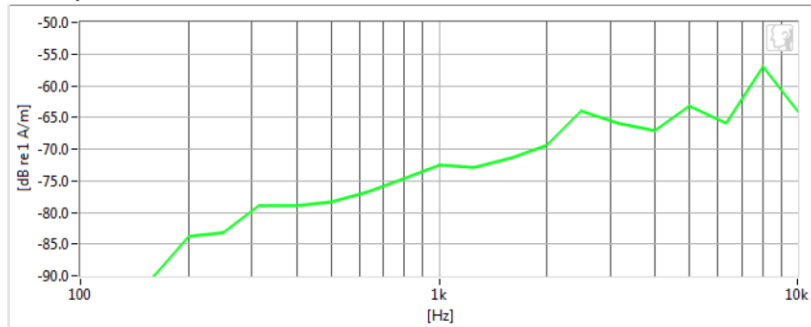
Type: HH Coil  
Serial: 925

Measurement Standard: ANSI C63.19-2011

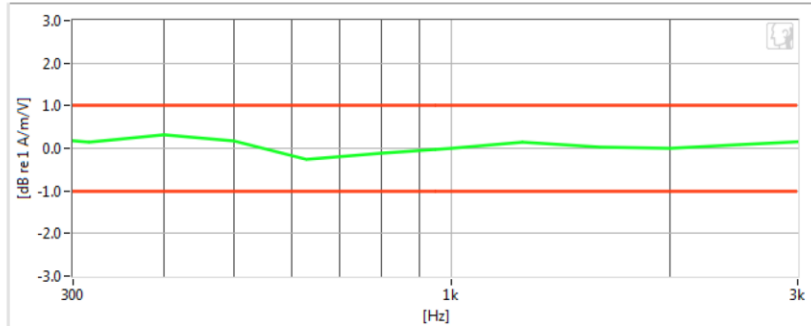
**Equipment:**

- Probe: Axial T-Coil Probe – SN: TEM-1124; Calibrated: 12/07/2016
- Helmholtz Coil – SN: 925; Calibrated: 12/07/2016

**Noise Spectrum**



**Frequency Response**



**Results**

Verification 1kHz Intensity	-10.185 dB	✓	Max/Min	-9.5/-10.5
Verification ABM2	-61.92 dB	✓	Maximum	-58.0
Frequency Response Margin	700m dB	✓	Tolerance curves	Aligned Data

PCTEST 2018

FCC ID: A3LSMG965U		HAC (T-COIL) TEST REPORT		Approved by: Quality Manager
Filename: 1M1808290175-02.A3L	Test Dates: 9/3/2018 - 9/5/2018	DUT Type: Portable Handset		Page 29 of 45

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**PCTEST Hearing-Aid Compatibility Facility**

**DUT: HH Coil – SN: 925**

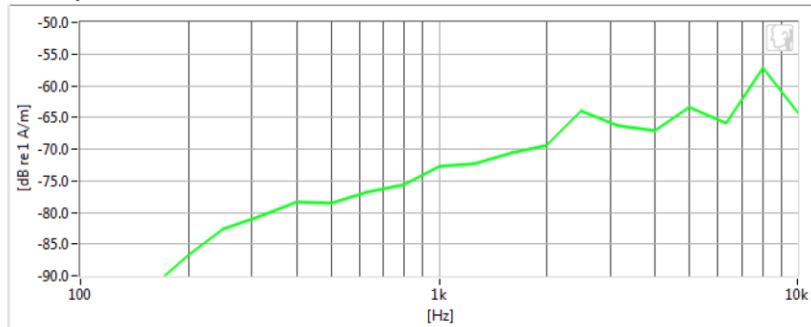
Type: HH Coil  
Serial: 925

Measurement Standard: ANSI C63.19-2011

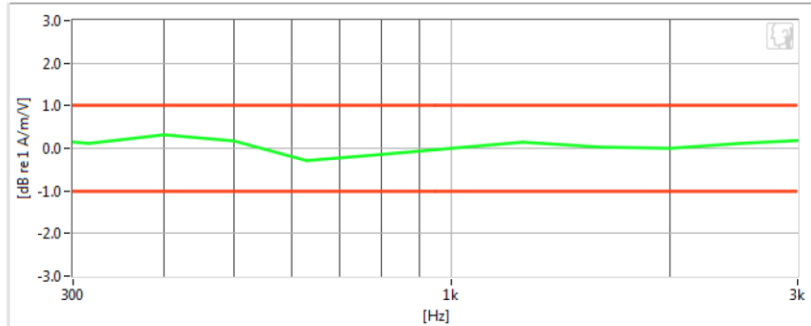
**Equipment:**

- Probe: Radial T-Coil Probe – SN: TEM-1130; Calibrated: 12/07/2016
- Helmholtz Coil – SN: 925; Calibrated: 12/07/2016

**Noise Spectrum**



**Frequency Response**



**Results**

Verification 1kHz Intensity	-10.277 dB	✓	Max/Min	-9.5/-10.5
Verification ABM2	-62.02 dB	✓	Maximum	-58.0
Frequency Response Margin	700m dB	✓	Tolerance curves	Aligned Data

PCTEST 2018

FCC ID: A3LSMG965U		HAC (T-COIL) TEST REPORT		Approved by: Quality Manager
Filename: 1M1808290175-02.A3L	Test Dates: 9/3/2018 - 9/5/2018	DUT Type: Portable Handset		Page 30 of 45

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**PCTEST Hearing-Aid Compatibility Facility**

**DUT: A3LSMG965U**

Type: Portable Handset  
Serial: 37038

**Measurement Standard:** ANSI C63.19-2011 / CTIA HAC Test Plan v3.1

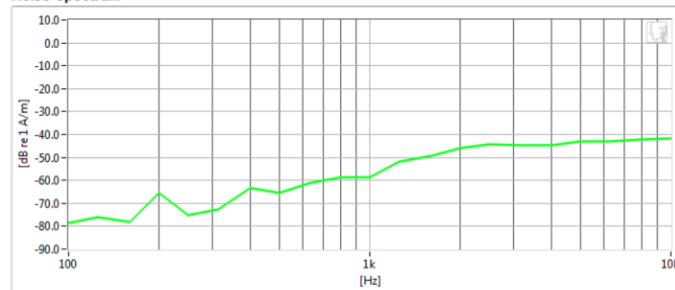
**Equipment:**

- Probe: Axial T-Coil Probe – SN: TEM-1124; Calibrated: 12/07/2016

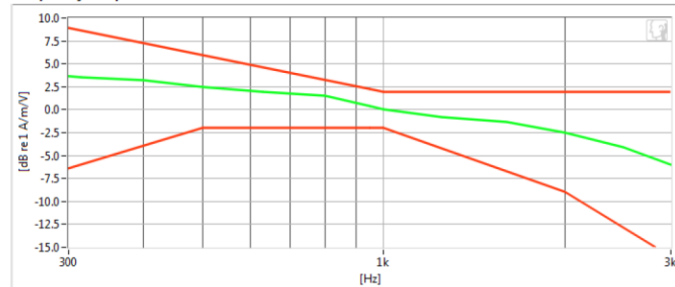
**Test Configuration:**

- Mode: LTE Band 41 PC2
- Bandwidth: 5MHz
- Channel: 40620
- Speech Signal: 3GPP2 Normal Test Signal

**Noise Spectrum**



**Frequency Response**



**Results**

ABM1	2.61 dB	✓	Minimum	-18.0
ABM2	-42.38 dB	✓	Maximum	0.0
SNNR	44.99 dB	✓	Minimum	20.0
Aligned Response - Normal	1.75 dB	✓	Tolerance curves	Aligned Data

PCTEST 2018

<b>FCC ID:</b> A3LSMG965U		<b>HAC (T-COIL) TEST REPORT</b>		<b>Approved by:</b> Quality Manager
<b>Filename:</b> 1M1808290175-02.A3L	<b>Test Dates:</b> 9/3/2018 - 9/5/2018	<b>DUT Type:</b> Portable Handset	Page 31 of 45	

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**PCTEST Hearing-Aid Compatibility Facility**

**DUT: A3LSMG965U**

Type: Portable Handset

Serial: 37038

**Measurement Standard:** ANSI C63.19-2011 / CTIA HAC Test Plan v3.1

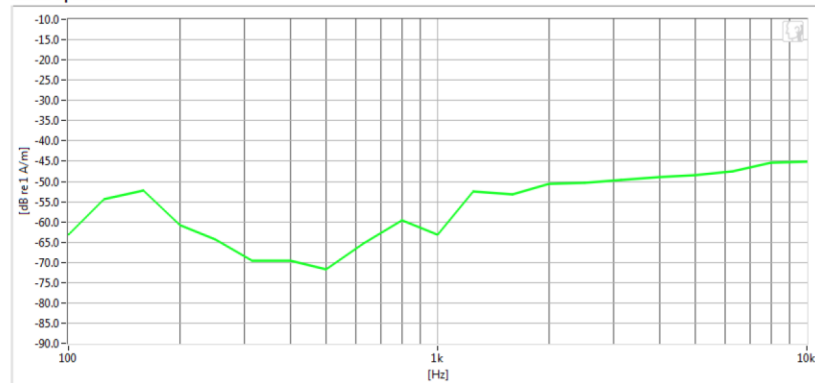
**Equipment:**

- Probe: Radial T-Coil Probe – SN: TEM-1130; Calibrated: 12/07/2016

**Test Configuration:**

- Mode: LTE Band 41 PC2
- Bandwidth: 5MHz
- Channel: 40185

**Noise Spectrum**



**Results**

ABM1	-4.24 dB	✓	Minimum	-18.0
ABM2	-43.52 dB	✓	Maximum	0.0
SNNR	39.27 dB	✓	Minimum	20.0

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<b>FCC ID:</b> A3LSMG965U		<b>HAC (T-COIL) TEST REPORT</b>		<b>Approved by:</b> Quality Manager
<b>Filename:</b> 1M1808290175-02.A3L	<b>Test Dates:</b> 9/3/2018 - 9/5/2018	<b>DUT Type:</b> Portable Handset	Page 32 of 45	



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# 10. CALIBRATION CERTIFICATES

<b>FCC ID:</b> A3LSMG965U		<b>HAC (T-COIL) TEST REPORT</b>		<b>Approved by:</b> Quality Manager
<b>Filename:</b> 1M1808290175-02.A3L	<b>Test Dates:</b> 9/3/2018 - 9/5/2018	<b>DUT Type:</b> Portable Handset	Page 33 of 45	

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West Caldwell Calibration Laboratories Inc.

# Certificate of Calibration

for

AXIAL T COIL PROBE

Manufactured by: TEM CONSULTING  
Model No: AXIAL T COIL PROBE  
Serial No: TEM-1124  
Calibration Recall No: 27068

Submitted By:

Customer: ANDREW HARWELL  
Company: PCTEST ENGINEERING LAB  
Address: 6660-B DOBBIN ROAD  
COLUMBIA MD 21045

The subject instrument was calibrated to the indicated specification using standards traceable to the National Institute of Standards and Technology or to accepted values of natural physical constants. This document certifies that the instrument met the following specification upon its return to the submitter.

West Caldwell Calibration Laboratories Procedure No. AXIAL T C TEM C

Upon receipt for Calibration, the instrument was found to be:

Within ( X )

*Handwritten signature*  
12/29/2016

tolerance of the indicated specification. See attached Report of Calibration.

West Caldwell Calibration Laboratories' calibration control system meets the following requirements, ISO 10012-1 MIL STD 45662A, ANSI/NCSL Z540-1, IEC Guide 25, ISO 9001:2008 and ISO 17025

Note: With this Certificate, Report of Calibration is included.

Approved by:

Calibration Date: 07-Dec-16

*FC*

Certificate No: 27068 -3

Felix Christopher (QA Mgr.)

QA Doc. #1051 Rev. 2.0 10/1/01

Certificate Page 1 of 1

ISO/IEC 17025:2005

**West Caldwell Calibration Laboratories, Inc.**  
uncompromised calibration  
1575 State Route 96, Victor, NY 14564, U.S.A.



Calibration Lab. Cert. # 1533.01

FCC ID: A3LSMG965U	PCTEST ENGINEERING LABORATORY, INC.	HAC (T-COIL) TEST REPORT		Approved by: Quality Manager
Filename: 1M1808290175-02.A3L	Test Dates: 9/3/2018 - 9/5/2018	DUT Type: Portable Handset		Page 34 of 45

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## REPORT OF CALIBRATION

TEM Consulting LP Axial T Coil Probe

for  
Model No.: Axial T Coil Probe

Serial No.: TEM 1124

Company : PCTEST Engineering Lab.

I. D. No: 80578

Calibration results:			
Probe Sensitivity measured with Helmholtz Coil			
<b>Helmholtz Coil;</b>			
the number of turns on each coil;	10	No.	Before & after data same: ... X.....
the radius of each coil, in meters;	0.204	m	
the current in the coils, in amperes.;	0.09	A	
<b>Helmholtz Coil Constant;</b>	7.09	A/m/V	Laboratory Environment:
<b>Helmholtz Coil magnetic field;</b>	5.98	A/m	Ambient Temperature: 20.2 °C
			Ambient Humidity: 31.4 % RH
			Ambient Pressure: 99.1 kPa
			Calibration Date: 7-Dec-16
Probe Sensitivity at	1000	Hz.	Report Number: 27068 -3
was	-60.23	dBV/A/m	Control Number: 27068
	0.974	mV/A/m	
Probe resistance	904	Ohms	

The above listed instrument meets or exceeds the tested manufacturer's specifications.

This Calibration is traceable through NIST test numbers: 683/284413-14

The expanded uncertainty of calibration: 0.30dB at 95% confidence level with a coverage factor of k=2.

Graph represents Probes Frequency Response.



The above listed instrument was checked using calibration procedure documented in West Caldwell Calibration Laboratories Inc. procedure :

Rev. 7.0 Jan. 24, 2014 Doc. # 1038 HCATEMC

Calibration was performed by West Caldwell Calibration Laboratories Inc. under Operating Procedures intended to implement the requirements of ISO10012-1, IEC Guide 25, ANSI/NCCL Z540-1, (MIL-STD-45662A) and ISO 9001:2008, ISO 17025

Cal. Date: 7-Dec-2016

Measurements performed by: FC

Calibrated on WCCL system type 9700

**Felix Christopher**

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Rev. 7.0 Jan. 24, 2014 Doc. # 1038 HCATEMC

FCC ID: A3LSMG965U	PCTEST ENGINEERING LABORATORY, INC.	HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename: 1M1808290175-02.A3L	Test Dates: 9/3/2018 - 9/5/2018	DUT Type: Portable Handset		Page 35 of 45

West Caldwell Calibration Laboratories Inc.

1575 State Route 96, Victor NY 14564  
Tel. (585) 586-3900 FAX (585) 586-4327

**Calibration Data Record**

TEM Consulting LP Axial T Coil Probe

for  
Model No.: Axial T Coil Probe

Serial No.: TEM 1124

Company : PCTEST Engineering Lab.

Test	Function	Tolerance	Measured values		
			Before	Out	Remarks
1.0	Probe Sensitivity at	1000 Hz. $\pm$ BVIA/m	-60.23		
2.0	Probe Level Linearity	Ref. (0 $\pm$ B)	$\pm$ B		
			6	6.03	
			0	0.00	
			-6	-6.03	
			-12	-12.05	
3.0	Probe Frequency Response	Ref. (0 $\pm$ B)	Hz		
			100	-19.8	
			126	-18.0	
			158	-16.0	
			200	-13.9	
			251	-12.0	
			316	-9.9	
			398	-8.0	
			501	-6.0	
			631	-4.0	
			794	-2.0	
			1000	0.0	
			1259	2.0	
			1585	4.0	
			1995	6.0	
			2512	7.9	
			3162	9.9	
			3981	11.9	
5012	13.9				
6310	15.9				
7943	18.0				
10000	20.2				



Instruments used for calibration:		S/N	Date of Cal.	Traceability No.	Due Date
HP	34401A	36064102	1-Oct-2016	,287708	1-Oct-2017
HP	34401A	36102471	1-Oct-2016	,287708	1-Oct-2017
HP	33120A	36043716	1-Oct-2016	,287708	1-Oct-2017
B&K	2133	1583254	1-Oct-2016	683/284413-14	1-Oct-2017

Cal. Date: 7-Dec-2016  
Calibrated on WCCL system type 9700

Tested by: Felix Christopher

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Rev. 7.0 Jan. 24, 2014 Doc. #1038 HCATEMC

FCC ID: A3LSMG965U	 PCTEST ENGINEERING LABORATORY, INC.	HAC (T-COIL) TEST REPORT		Approved by: Quality Manager
Filename: 1M1808290175-02.A3L	Test Dates: 9/3/2018 - 9/5/2018	DUT Type: Portable Handset		Page 36 of 45

West Caldwell Calibration Laboratories Inc.

# Certificate of Calibration

for

## RADIAL T COIL PROBE

Manufactured by: TEM CONSULTING  
Model No: RADIAL T COIL PROBE  
Serial No: TEM-1130  
Calibration Recall No: 27068

### Submitted By:

Customer: ANDREW HARWELL  
Company: PCTEST ENGINEERING LAB  
Address: 6660-B DOBBIN ROAD  
COLUMBIA MD 21045

The subject instrument was calibrated to the indicated specification using standards traceable to the National Institute of Standards and Technology or to accepted values of natural physical constants. This document certifies that the instrument met the following specification upon its return to the submitter.

West Caldwell Calibration Laboratories Procedure No. RADIAL T TEM C

Upon receipt for Calibration, the instrument was found to be:

Within ( X )

tolerance of the indicated specification. See attached Report of Calibration.

West Caldwell Calibration Laboratories' calibration control system meets the following requirements, ISO 10012-1 MIL STD 45662A, ANSI/NC SL Z540-1, IEC Guide 25, ISO 9001:2008 and ISO 17025

Note: With this Certificate, Report of Calibration is included.

Approved by:

Calibration Date: 07-Dec-16

FC

Certificate No: 27068 -2

Felix Christopher (QA Mgr.)  
ISO/IEC 17025:2005

QA Doc. #1091 Rev. 2.0 10/1/01

Certificate Page 1 of 1

**West Caldwell Calibration Laboratories, Inc.**  
uncompromised calibration  
1575 State Route 96, Victor, NY 14564, U.S.A.



Calibration Lab. Cert. # 1533.01

FCC ID: A3LSMG965U	PCTEST ENGINEERING LABORATORY, INC.	HAC (T-COIL) TEST REPORT		Approved by: Quality Manager
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1575 State Route 96, Victor NY 14564

ISO/IEC 17025: 2005



Calibration Lab. Cert. # 1533.01

## REPORT OF CALIBRATION

TEM Consulting LP Radial T Coil Probe

Model No.: Radial T Coil Probe

Serial No.: TEM-1130

Company : PCTEST Engineering Lab.

I. D. No: 80579

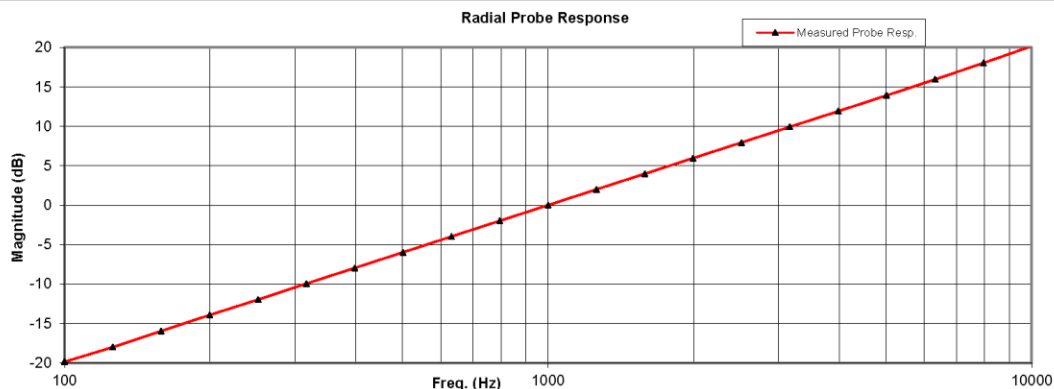
Calibration results:			
Probe Sensitivity measured with Helmholtz Coil			
<b>Helmholtz Coil;</b>			
the number of turns on each coil;	10	No.	Before & after data same: ...X.....
the radius of each coil, in meters;	0.204	m	
the current in the coils, in amperes.;	0.09	A	
<b>Helmholtz Coil Constant;</b>	7.09	A/m/V	Laboratory Environment:
<b>Helmholtz Coil magnetic field;</b>	5.98	A/m	Ambient Temperature: 20.2 °C
			Ambient Humidity: 31.4 % RH
			Ambient Pressure: 99.1 kPa
			Calibration Date: 7-Dec-16
Probe Sensitivity at	1000	Hz.	Report Number: 27068 -2
was	-60.27	dBV/A/m	Control Number: 27068
	0.969	mV/A/m	
Probe resistance	902	Ohms	

The above listed instrument meets or exceeds the tested manufacturer's specifications.

This Calibration is traceable through NIST test numbers: 683/284413-14

The expanded uncertainty of calibration: 0.30dB at 95% confidence level with a coverage factor of k=2.

Graph represents Probes Frequency Response.



The above listed instrument was checked using calibration procedure documented in West Caldwell Calibration Laboratories Inc. procedure :

Rev. 7.0 Jan. 24, 2014 Doc. # 1038 HCRTEMC

Calibration was performed by West Caldwell Calibration Laboratories Inc. under Operating Procedures intended to implement the requirements of ISO10012-1, IEC Guide 25, ANSI/NCCL Z540-1, (MIL-STD-45662A) and ISO 9001:2008, ISO 17025

Cal. Date: 7-Dec-2016

Measurements performed by: FC

Calibrated on WCCL system type 9700

Felix Christopher

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Rev. 7.0 Jan. 24, 2014 Doc. # 1038 HCRTEMC

FCC ID: A3L5MG965U	PCTEST ENGINEERING LABORATORY, INC.	HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename: 1M1808290175-02.A3L	Test Dates: 9/3/2018 - 9/5/2018	DUT Type: Portable Handset		Page 38 of 45

West Caldwell Calibration Laboratories Inc.

1575 State Route 96, Victor NY 14564  
Tel. (585) 586-3900 FAX (585) 586-4327

**Calibration Data Record**

TEM Consulting LP Radial T Coil Probe

Model No.: Radial T Coil Probe

Serial No.: TEM-1130

Company : PCTEST Engineering Lab.

Test	Function	Tolerance	Measured values		
			Before	Out	Remarks
1.0	Probe Sensitivity at	1000 Hz. $\pm$ BVIA/m	-60.27		
2.0	Probe Level Linearity	Ref. (0 $\pm$ B)	$\pm$ B		
			6	6.03	
			0	0.00	
			-6	-6.03	
			-12	-12.06	
3.0	Probe Frequency Response	Ref. (0 $\pm$ B)	Hz		
			100	-19.9	
			126	-18.0	
			158	-16.0	
			200	-13.9	
			251	-12.0	
			316	-10.0	
			398	-8.0	
			501	-6.0	
			631	-4.0	
			794	-2.0	
			1000	0.0	
			1259	2.0	
			1585	4.0	
			1995	6.0	
			2512	7.9	
			3162	9.9	
			3981	11.9	
5012	13.9				
6310	15.9				
7943	18.0				
10000	20.2				



Instruments used for calibration:		S/N	Date of Cal.	Traceability No.	Due Date
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HP	34401A	36102471	1-Oct-2016	,287708	1-Oct-2017
HP	33120A	36043716	1-Oct-2016	,287708	1-Oct-2017
B&K	2133	1583254	1-Oct-2016	683/284413-14	1-Oct-2017

Cal. Date: 7-Dec-2016  
Calibrated on WCCL system type 9700

Tested by: Felix Christopher

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## 11. CONCLUSION

The measurements taken in accordance with the procedures provided in the CTIA Test Plan for Hearing Aid Compatibility Rev 3.1.1, May 2017, indicate that the LTE TDD Band 41 of the wireless communications device comply with the HAC limits specified in the ANSI C63.19 Standard and FCC WT Docket No. 01-309 RM-8658. Precise laboratory measures were taken to assure repeatability of the tests. The tested device complies with the requirements in respect to all parameters specific to the test. The test results and statements relate only to the item(s) tested.

The measurement system and techniques presented in this evaluation are proposed in the ANSI standard as a means of best approximating wireless device compatibility with a hearing-aid. The literature is under continual re-construction.

<b>FCC ID:</b> A3LSMG965U		<b>HAC (T-COIL) TEST REPORT</b>		<b>Approved by:</b> Quality Manager
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## 12. REFERENCES

1. ANSI C63.19-2011, American National Standard for Methods of Measurement of Compatibility between Wireless communication devices and Hearing Aids., New York, NY, IEEE, May 2011
2. CTIA Certification Program, "Test Plan for Hearing Aid Compatibility Rev 3.1.1", Washington, DC, CTIA, May 2017
3. FCC Office of Engineering and Technology KDB, "285076 D01 HAC Guidance v05," September 13, 2017
4. FCC Office of Engineering and Technology KDB, "285076 D02 T-Coil Testing for CMRS IP v03," September 13, 2017
5. FCC Public Notice DA 06-1215, *Wireless Telecommunications Bureau and Office of Engineering and Technology Clarify Use of Revised Wireless Phone Hearing Aid Compatibility Standard*, June 6, 2006
6. FCC 3G Review Guidance, Laboratory Division OET FCC, May/June 2006
7. Berger, H. S., "Compatibility Between Hearing Aids and Wireless Devices," Electronic Industries Forum, Boston, MA, May, 1997
8. Berger, H. S., "Hearing Aid and Cellular Phone Compatibility: Working Toward Solutions," Wireless Telephones and Hearing Aids: New Challenges for Audiology, Gallaudet University, Washington, D.C., May, 1997 (To be reprinted in the American Journal of Audiology).
9. Berger, H. S., "Hearing Aid Compatibility with Wireless Communications Devices," IEEE International Symposium on Electromagnetic Compatibility, Austin, TX, August, 1997.
10. Bronaugh, E. L., "Simplifying EMI Immunity (Susceptibility) Tests in TEM Cells," in the 1990 IEEE International Symposium on Electromagnetic Compatibility Symposium Record, Washington, D.C., August 1990, pp. 488-491
11. Byrne, D. and Dillon, H., The National Acoustics Laboratory (NAL) New Procedure for Selecting the Gain and Frequency Response of a Hearing Aid, Ear and Hearing 7:257-265, 1986.
12. Crawford, M. L., "Measurement of Electromagnetic Radiation from Electronic Equipment using TEM Transmission Cells," U.S. Department of Commerce, National Bureau of Standards, NBSIR 73-306, Feb. 1973.
13. Crawford, M. L., and Workman, J. L., "Using a TEM Cell for EMC Measurements of Electronic Equipment," U.S. Department of Commerce, National Bureau of Standards. Technical Note 1013, July 1981.
14. EHIMA GSM Project, Development phase, Project Report (1<sup>st</sup> part) Revision A. Technical-Audiological Laboratory and Telecom Denmark, October 1993.
15. EHIMA GSM Project, Development phase, Part II Project Report. Technical-Audiological Laboratory and Telecom Denmark, June 1994.
16. EHIMA GSM Project Final Report, Hearing Aids and GSM Mobile Telephones: Interference Problems, Methods of Measurement and Levels of Immunity. Technical-Audiological Laboratory and Telecom Denmark, 1995.
17. HAMPIS Report, Comparison of Mobile phone electromagnetic near field with an upscaled electromagnetic far field, using hearing aid as reference, 21 October 1999.
18. Hearing Aids/GSM, Report from OTWIDAM, Technical-Audiological Laboratory and Telecom Denmark, April 1993.
19. IEEE 100, The Authoritative Dictionary of IEEE Standards Terms, Seventh Edition.
20. Joyner, K. H, et. al., Interference to Hearing Aids by the New Digital Mobile Telephone System, Global System for Mobile (GSM) Communication Standard, National Acoustic Laboratory, Australian Hearing Series, Sydney 1993.
21. Joyner, K. H., et. al., Interference to Hearing Aids by the Digital Mobile Telephone System, Global System for Mobile Communications (GSM), NAL Report #131, National Acoustic Laboratory, Australian Hearing Series, Sydney, 1995.
22. Kecker, W. T., Crawford, M. L., and Wilson, W. A., "Construction of a Transverse Electromagnetic Cell", U.S. Department of Commerce, National Bureau of Standards, Technical Note 1011, Nov. 1978.



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23. Konigstein, D., and Hansen, D., "A New Family of TEM Cells with enlarged bandwidth and Optimized working Volume," in the Proceedings of the 7<sup>th</sup> International Symposium on EMC, Zurich, Switzerland, March 1987; 50:9, pp. 127-132.
24. Kuk, F., and Hjorstgaard, N. K., "Factors affecting interference from digital cellular telephones," Hearing Journal, 1997; 50:9, pp 32-34.
25. Ma, M. A., and Kanda, M., "Electromagnetic Compatibility and Interference Metrology," U.S. Department of Commerce, National Bureau of Standards, Technical Note 1099, July 1986, pp. 17-43.
26. Ma, M. A., Sreenivashiah, I. , and Chang, D. C., "A Method of Determining the Emission and Susceptibility Levels of Electrically Small Objects Using a TEM Cell," U.S. Department of Commerce, National Bureau of Standards, Technial Note 1040, July 1981.
27. McCandless, G. A., and Lyregaard, P. E., Prescription of Gain/Output (POGO) for Hearing Aids, Hearing Instruments 1:16-21, 1983
28. Skopec, M., "Hearing Aid Electromagnetic Interference from Digital Wireless Telephones, "IEEE Transactions on Rehabilitation Engineering, vol. 6, no. 2, pp. 235-239, June 1998.
29. Technical Report, GSM 05.90, GSM EMC Considerations, European Telecommunications Standards Institute, January 1993.
30. Victorian, T. A., "Digital Cellular Telephone Interference and Hearing Aid Compatibility—an Update," Hearing Journal 1998; 51:10, pp. 53-60
31. Wong, G. S. K., and Embleton, T. F. W., eds., AIP Handbook of Condenser Microphones: Theory, Calibration and Measurements, AIP Press.

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